

ABSTRACT OF THE DISCLOSURE

[0049] A spectrometer may include a radiant source configured to emit radiation and an optical amplifier configured to amplify the radiation emitted by the radiant source to produce amplified radiation. A number of optical elements may be configured to produce an interference pattern from the amplified radiation. A detector may detect the interference pattern and generate data from the interference pattern. A processor may be configured to measure one or more lengths from the data.

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